Prof. Lloyd Massengill (PhD, NCSU, 1987) has devoted four decades to the research and development of high-reliability circuit modeling, simulation, and design. In 1987 he established the Radiation Effects and Reliability program at Vanderbilt University, where he currently serves as Professor of Electrical and Computer Engineering. In 2003, he helped found the Vanderbilt Institute for Space and Defense Electronics, which provides fundamental research in the area of radiation effects on integrated circuits. From 2003 to 2015, he served as the Director of Engineering at ISDE where he oversaw research and development activities from nano-scale integrated circuit radiation effects failure risk assessment for agencies such as DARPA, DTRA and NRO, to the support of high-reliability weapons systems for the U.S. Navy and U.S. Air Force. Dr. Massengill founded Reliable MicroSystems in early 2016 to meet customer-driven needs for the application of advances in fundamental research to applied fault tolerant system design, both commercial and DoD.

Dr. Massengill is a Fellow of the IEEE, and recipient of the IEEE Radiation Effects Award and the HEART Peter Haas Award.